

# CD54HC173, CD74HC173, CD54HCT173

Data sheet acquired from Harris Semiconductor SCHS158E

February 1998 - Revised October 2003

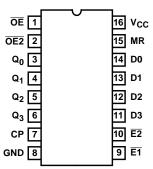
# High-Speed CMOS Logic Quad D-Type Flip-Flop, Three-State

#### Features

- Three-State Buffered Outputs
- Gated Input and Output Enables
- Fanout (Over Temperature Range)
  - Standard Outputs...... 10 LSTTL Loads
  - Bus Driver Outputs ...... 15 LSTTL Loads
- Wide Operating Temperature Range ...-55°C to 125°C
- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- HC Types
  - 2V to 6V Operation
  - High Noise Immunity:  $N_{IL}$  = 30%,  $N_{IH}$  = 30% of  $V_{CC}$  at  $V_{CC}$  = 5V
- HCT Types
  - 4.5V to 5.5V Operation
  - Direct LSTTL Input Logic Compatibility, V<sub>IL</sub>= 0.8V (Max), V<sub>IH</sub> = 2V (Min)
  - CMOS Input Compatibility,  $I_I \le 1\mu A$  at  $V_{OL}$ ,  $V_{OH}$

#### **Pinout**

CD54HC173, CD54HCT173 (CERDIP) CD74HC173 (PDIP, SOIC, SOP, TSSOP) CD74HCT173 (PDIP, SOIC) TOP VIEW



### Description

The 'HC173 and 'HCT173 high speed three-state quad D-type flip-flops are fabricated with silicon gate CMOS technology. They possess the low power consumption of standard CMOS Integrated circuits, and can operate at speeds comparable to the equivalent low power Schottky devices. The buffered outputs can drive 15 LSTTL loads. The large output drive capability and three-state feature make these parts ideally suited for interfacing with bus lines in bus oriented systems.

The four D-type flip-flops operate synchronously from a common clock. The outputs are in the three-state mode when either of the two output disable pins are at the logic "1" level. The input ENABLES allow the flip-flops to remain in their present states without having to disrupt the clock If either of the 2 input ENABLES are taken to a logic "1" level, the Q outputs are fed back to the inputs, forcing the flip-flops to remain in the same state. Reset is enabled by taking the MASTER RESET (MR) input to a logic "1" level. The data outputs change state on the positive going edge of the clock.

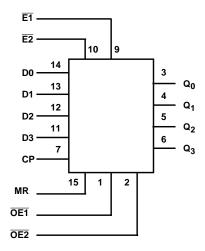
The 'HCT173 logic family is functionally, as well as pin compatible with the standard LS logic family.

## **Ordering Information**

PART NUMBER	TEMP. RANGE (°C)	PACKAGE
CD54HC173F3A	-55 to 125	16 Ld CERDIP
CD54HCT173F3A	-55 to 125	16 Ld CERDIP
CD74HC173E	-55 to 125	16 Ld PDIP
CD74HC173M	-55 to 125	16 Ld SOIC
CD74HC173MT	-55 to 125	16 Ld SOIC
CD74HC173M96	-55 to 125	16 Ld SOIC
CD74HC173NSR	-55 to 125	16 Ld SOP
CD74HC173PW	-55 to 125	16 Ld TSSOP
CD74HC173PWR	-55 to 125	16 Ld TSSOP
CD74HC173PWT	-55 to 125	16 Ld TSSOP
CD74HCT173E	-55 to 125	16 Ld PDIP
CD74HCT173M	-55 to 125	16 Ld SOIC
CD74HCT173MT	-55 to 125	16 Ld SOIC
CD74HCT173M96	-55 to 125	16 Ld SOIC

NOTE: When ordering, use the entire part number. The suffixes 96 and R denote tape and reel. The suffix T denotes a small-quantity reel of 250.

## Functional Diagram



**TRUTH TABLE** 

	INP				
		DATA E	NABLE	DATA	OUTPUT
MR	СР	E1	E2	D	Q <sub>n</sub>
Н	Х	Х	Х	Х	L
L	L	Х	Х	Х	$Q_0$
L	1	Н	Х	Х	$Q_0$
L	1	Х	Н	Х	$Q_0$
L	1	L	L	L	L
L	1	L	L	Н	Н

H= High Voltage Level

L = Low Voltage Level

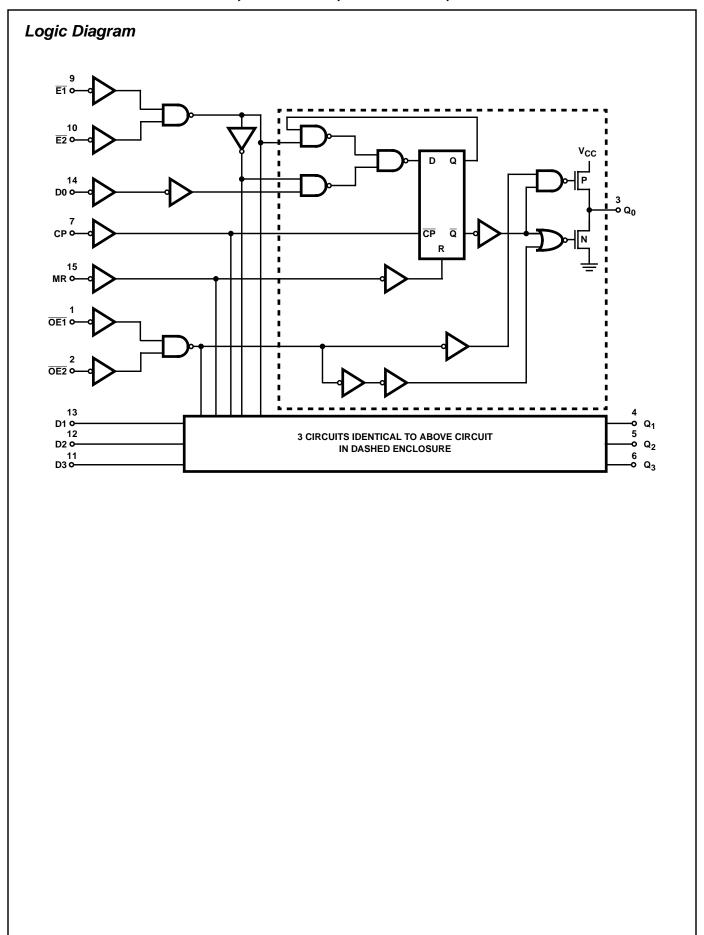
X= Irrelevant

↑= Transition from Low to High Level

 $\mathbf{Q}_0\mathbf{=}$  Level Before the Indicated Steady-State Input Conditions Were Established

NOTE:

When either OE1 or OE2 (or both) is (are) high, the output is disabled to the high-impedance state, however, sequential operation of the flip-flops is not affected.



## **Absolute Maximum Ratings**

#### 

#### **Thermal Information**

Package Thermal Impedance, θ <sub>JA</sub> (see Note 2):
E (PDIP) Package
M (SOIC) Package73°C/W
NS (SOP) Package
PW (TSSOP) Package 108 <sup>o</sup> C/W
Maximum Junction Temperature
Maximum Storage Temperature Range65°C to 150°C
Maximum Lead Temperature (Soldering 10s)300°C
(SOIC - Lead Tips Only)

#### **Operating Conditions**

Temperature Range (T <sub>A</sub> )55°C to 125°C
Supply Voltage Range, V <sub>CC</sub>
HC Types2V to 6V
HCT Types
DC Input or Output Voltage, V <sub>I</sub> , V <sub>O</sub> 0V to V <sub>CC</sub>
Input Rise and Fall Time
2V
4.5V 500ns (Max)
6V

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

#### NOTE:

2. The package thermal impedance is calculated in accordance with JESD 51-7.

### **DC Electrical Specifications**

		1	ST ITIONS			25°C		-40°C 1	O 85°C	-55°C TO 125°C		
PARAMETER	SYMBOL	V <sub>I</sub> (V)	I <sub>O</sub> (mA)	V <sub>CC</sub> (V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS
HC TYPES		-							-	-		
High Level Input	V <sub>IH</sub>	-	-	2	1.5	-	-	1.5	-	1.5	-	V
Voltage				4.5	3.15	-	-	3.15	-	3.15	-	V
				6	4.2	-	-	4.2	-	4.2	-	V
Low Level Input	V <sub>IL</sub>	-	-	2	ı	ı	0.5	-	0.5	-	0.5	V
Voltage				4.5	-	-	1.35	-	1.35	-	1.35	V
				6	-	-	1.8	-	1.8	-	1.8	V
High Level Output	V <sub>OH</sub>	V <sub>IH</sub> or V <sub>IL</sub>	-0.02	2	1.9	-	-	1.9	-	1.9	-	V
Voltage CMOS Loads			-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
			-0.02	6	5.9	-	-	5.9	-	5.9	-	V
High Level Output Voltage			-6	4.5	3.98	-	-	3.84	-	3.7	-	V
TTL Loads			-7.8	6	5.48	-	-	5.34	-	5.2	-	V
Low Level Output	V <sub>OL</sub>	V <sub>IH</sub> or	0.02	2	-	-	0.1	-	0.1	-	0.1	V
Voltage CMOS Loads		V <sub>IL</sub>	0.02	4.5	ı	ı	0.1	ı	0.1	-	0.1	V
			0.02	6	i	ı	0.1	ı	0.1	-	0.1	V
Low Level Output			6	4.5	ı	ı	0.26	-	0.33	-	0.4	V
Voltage TTL Loads			7.8	6	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	II	V <sub>CC</sub> or GND	-	6	-	-	±0.1	-	±1	-	±1	μА
Quiescent Device Current	Icc	V <sub>CC</sub> or GND	0	6	-	-	8	-	80	-	160	μА

## DC Electrical Specifications (Continued)

			ST ITIONS			25°C		-40°C TO 85°C		-55°C T	O 125°C	
PARAMETER	SYMBOL	V <sub>I</sub> (V)	I <sub>O</sub> (mA)	V <sub>CC</sub> (V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS
Three-State Leakage Current	loz	V <sub>IL</sub> or V <sub>IH</sub>	-	6	-	-	±0.5	-	±0.5	-	±10	μА
HCT TYPES												
High Level Input Voltage	V <sub>IH</sub>	-	-	4.5 to 5.5	2	-	-	2	-	2	-	V
Low Level Input Voltage	V <sub>IL</sub>	-	-	4.5 to 5.5	-	-	0.8	-	0.8	-	0.8	V
High Level Output Voltage CMOS Loads	V <sub>ОН</sub>	V <sub>IH</sub> or V <sub>IL</sub>	-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
High Level Output Voltage TTL Loads			-6	4.5	3.98	-	-	3.84	-	3.7	-	V
Low Level Output Voltage CMOS Loads	V <sub>OL</sub>	V <sub>IH</sub> or V <sub>IL</sub>	0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads			6	4.5	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	Iį	V <sub>CC</sub> to GND	0	5.5	-	-	±0.1	-	±1	-	±1	μА
Quiescent Device Current	Icc	V <sub>CC</sub> or GND	0	5.5	-	-	8	-	80	-	160	μА
Additional Quiescent Device Current Per Input Pin: 1 Unit Load	ΔI <sub>CC</sub> (Note 3)	V <sub>CC</sub> -2.1	-	4.5 to 5.5	-	100	360	-	450	-	490	μА
Three-State Leakage Current	l <sub>OZ</sub>	V <sub>IL</sub> or V <sub>IH</sub>	-	5.5	-	-	±0.5	-	±5.0	-	±10	μА

#### NOTE:

## **HCT Input Loading Table**

INPUT	UNIT LOADS					
D0-D3	0.15					
E1 and E2	0.15					
СР	0.25					
MR	0.2					
OE1 and OE2	0.5					

NOTE: Unit Load is  $\Delta I_{CC}$  limit specified in DC Electrical Specifications table, e.g., 360 $\mu A$  max at 25°C.

<sup>3.</sup> For dual-supply systems theoretical worst case ( $V_I$  = 2.4V,  $V_{CC}$  = 5.5V) specification is 1.8mA.

## **Switching Specifications** Input $t_r$ , $t_f = 6ns$

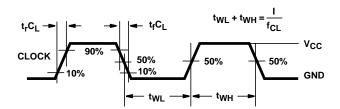
		TEST		25	°C	-40°C TO 85°C	-55°C TO 125°C	
PARAMETER	SYMBOL	CONDITIONS	V <sub>CC</sub> (V)	TYP	MAX	MAX	MAX	UNITS
HC TYPES		•			!	•	!	
Propagation Delay, Clock to	t <sub>PLH</sub> , t <sub>PHL</sub>	C <sub>L</sub> = 50pF	2	-	200	250	300	ns
Output			4.5	-	40	50	60	ns
		C <sub>L</sub> = 15pF	5	17	-	-	-	ns
		CL = 50pF	6	-	34	43	51	ns
Propagation Delay, MR to	t <sub>PHL</sub>	C <sub>L</sub> = 50pF	2	-	175	220	265	ns
Output			4.5	-	35	44	53	ns
		C <sub>L</sub> = 15pF	5	12	-	-	-	ns
		CL = 50pF	6	-	30	37	45	ns
Propagation Delay Output	t <sub>PLZ</sub> , t <sub>PHZ</sub>	CL = 50pF	2		150	190	225	ns
Enable to Q (Figure 6)	<sup>t</sup> PZL <sup>, t</sup> PZH	C <sub>L</sub> = 50pF	4.5		30	38	45	ns
		C <sub>L</sub> = 15pF	5	12	-	-	-	ns
		CL = 50pF	6		26	33	38	ns
Output Transition Times	t <sub>TLH</sub> , t <sub>THL</sub>	C <sub>L</sub> = 50pF	2	-	60	75	90	ns
			4.5	-	12	15	18	ns
			6	-	10	13	15	ns
Maximum Clock Frequency	f <sub>MAX</sub>	C <sub>L</sub> = 15pF	5	60	-	-	-	MHz
Input Capacitance	C <sub>IN</sub>	-	-	-	10	10	10	pF
Three-State Output Capacitance	c <sub>o</sub>	-	-	-	10	10	10	pF
Power Dissipation Capacitance (Notes 4, 5)	C <sub>PD</sub>	-	5	29	-	-	-	pF
HCT TYPES	•				•			
Propagation Delay, Clock to	t <sub>PLH</sub> , t <sub>PHL</sub>	C <sub>L</sub> = 50pF	4.5	-	40	50	60	ns
Capacitance Notes 4, 5)		C <sub>L</sub> = 15pF	5	17	-	-	-	ns
Propagation Delay, MR to	t <sub>PHL</sub>	$C_L = 50pF$	4.5	ı	44	55	66	ns
Output		C <sub>L</sub> = 15pF	5	18	-	-	-	ns
Propagation Delay Output	t <sub>PZL</sub> , t <sub>PZH</sub>	CL = 50pF	2		150	190	225	ns
Enable to Q (Figure 6)		C <sub>L</sub> = 50pF	4.5		30	38	45	ns
		C <sub>L</sub> = 15pF	5	14	-	-	-	ns
		CL = 50pF	6		26	33	38	ns
Output Transition Times	t <sub>TLH</sub> , t <sub>THL</sub>	C <sub>L</sub> = 50pF	4.5	-	15	19	22	ns
Maximum Clock Frequency	f <sub>MAX</sub>	C <sub>L</sub> = 15pF	5	60	-	-	-	MHz
Input Capacitance	C <sub>IN</sub>	-	-	-	10	10	10	pF
Power Dissipation Capacitance (Notes 4, 5)	C <sub>PD</sub>	-	5	34	-	-	-	pF

 <sup>4.</sup> C<sub>PD</sub> is used to determine the dynamic power consumption, per package.
 5. P<sub>D</sub> = V<sub>CC</sub><sup>2</sup> f<sub>i</sub> + ∑ (C<sub>L</sub> V<sub>CC</sub><sup>2</sup> + f<sub>O</sub>) where f<sub>i</sub> = Input Frequency, f<sub>O</sub> = Input Frequency, C<sub>L</sub> = Output Load Capacitance, V<sub>CC</sub> = Supply Voltage.

## **Prerequisite For Switching Specifications**

			25	oc	-40°C T	O 85°C	-55°C T	O 125 <sup>0</sup> C	
PARAMETER	SYMBOL	V <sub>CC</sub> (V)	MIN	MAX	MIN	MAX	MIN	MAX	UNITS
HC TYPES				•					
Maximum Clock Frequency	f <sub>MAX</sub>	2	6	-	5	-	4	-	MHz
		4.5	30	-	24	-	20	-	MHz
		6	35	-	28	-	24	-	MHz
MR Pulse Width	t <sub>w</sub>	2	80	-	100	-	120	-	ns
		4.5	16	-	20	-	24	-	ns
		6	14	-	17	-	20	-	ns
Clock Pulse Width	t <sub>w</sub>	2	80	-	100	-	120	-	ns
		4.5	16	-	20	-	24	-	ns
		6	14	-	17	-	20	-	ns
Set-up Time, Data to Clock	t <sub>SU</sub>	2	60	-	75	-	90	-	ns
and $\overline{\mathbb{E}}$ to Clock		4.5	12	-	15	-	18	-	ns
		6	10	-	13	-	15	-	ns
Hold Time, Data to Clock	t <sub>H</sub>	2	3	-	3	-	3	-	ns
		4.5	3	-	3	-	3	-	ns
		6	3	-	3	-	3	-	ns
Hold Time, E to Clock	t <sub>H</sub>	2	0	-	0	-	0	-	ns
		4.5	0	-	0	-	0	-	ns
		6	0	-	0	-	0	-	ns
Removal Time, MR to Clock	t <sub>REM</sub>	2	60	-	75	-	90	-	ns
		4.5	12	-	15	-	18	-	ns
		6	10	-	13	-	15	-	ns
HCT TYPES						<u> </u>			
Maximum Clock Frequency	f <sub>MAX</sub>	4.5	20	-	16	-	13	-	MHz
MR Pulse Width	t <sub>w</sub>	4.5	15	-	19	-	22	-	ns
Clock Pulse Width	t <sub>w</sub>	4.5	25	-	31	-	38	-	ns
Set-up Time, $\overline{\overline{E}}$ to Clock	t <sub>SU</sub>	4.5	12	-	15	-	18	-	ns
Set-up Time, Data to Clock	t <sub>SU</sub>	4.5	18	-	23	-	27	-	ns
Hold Time, Data to Clock	t <sub>H</sub>	4.5	0	-	0	-	0	-	ns
Hold Time, E to Clock	t <sub>H</sub>	4.5	0	-	0	-	0	-	ns
Removal Time, MR to Clock	t <sub>REM</sub>	4.5	12	-	15	-	18	-	ns

## Test Circuits and Waveforms



NOTE: Outputs should be switching from 10% V $_{CC}$  to 90% V $_{CC}$  in accordance with device truth table. For f $_{MAX}$ , input duty cycle = 50%.

FIGURE 1. HC CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH

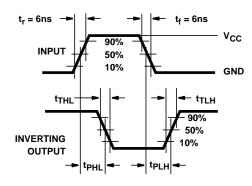


FIGURE 3. HC AND HCU TRANSITION TIMES AND PROPAGA-TION DELAY TIMES, COMBINATION LOGIC

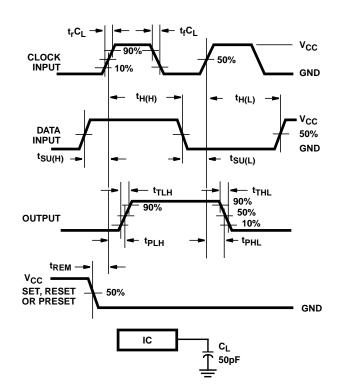
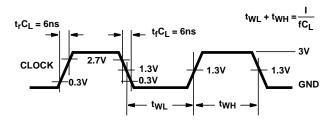


FIGURE 5. HC SETUP TIMES, HOLD TIMES, REMOVAL TIME, AND PROPAGATION DELAY TIMES FOR EDGE TRIGGERED SEQUENTIAL LOGIC CIRCUITS



NOTE: Outputs should be switching from 10% V $_{CC}$  to 90% V $_{CC}$  in accordance with device truth table. For f $_{MAX}$ , input duty cycle = 50%.

FIGURE 2. HCT CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH

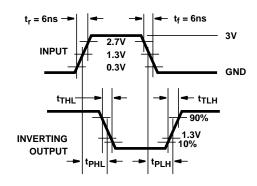


FIGURE 4. HCT TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

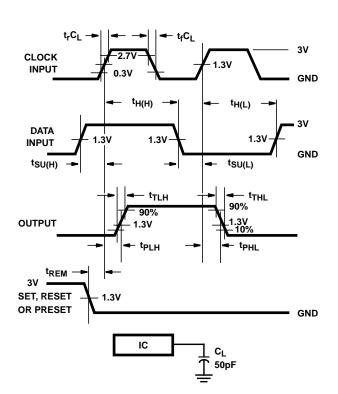


FIGURE 6. HCT SETUP TIMES, HOLD TIMES, REMOVAL TIME, AND PROPAGATION DELAY TIMES FOR EDGE TRIGGERED SEQUENTIAL LOGIC CIRCUITS

#### Test Circuits and Waveforms (Continued) 6ns 3V V<sub>CC</sub> OUTPUT OUTPUT 90% DISABLE 50% DISABLE 10% 0.3 GND GND t<sub>PZL</sub> → - t<sub>PLZ</sub> → t<sub>PZL</sub> ► t<sub>PLZ</sub> → **OUTPUT LOW** OUTPUT LOW 50% TO OFF TO OFF 1.3V 10% 10% ◆ t<sub>PHZ</sub> ◆ - t<sub>PZH</sub> · t<sub>PHZ</sub> → tpzh -90% 90% **OUTPUT HIGH OUTPUT HIGH** 50% TO OFF TO OFF 1.3V OUTPUTS **OUTPUTS OUTPUTS OUTPUTS**

**OUTPUTS** 

**ENABLED** 

FIGURE 7. HC THREE-STATE PROPAGATION DELAY **WAVEFORM** 

**ENABLED** 

**OUTPUTS** 

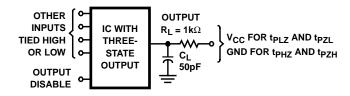
DISABLED

FIGURE 8. HCT THREE-STATE PROPAGATION DELAY **WAVEFORM** 

**DISABLED** 

**ENABLED** 

ENABLED



NOTE: Open drain waveforms  $t_{PLZ}$  and  $t_{PZL}$  are the same as those for three-state shown on the left. The test circuit is Output  $R_L = 1k\Omega$  to  $V_{CC}$ ,  $C_L = 50pF$ .

FIGURE 9. HC AND HCT THREE-STATE PROPAGATION DELAY TEST CIRCUIT





24-Aug-2018

## **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
5962-8682501EA	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-8682501EA CD54HC173F3A	Samples
5962-8875901EA	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-8875901EA CD54HCT173F3A	Samples
CD54HC173F	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	CD54HC173F	Samples
CD54HC173F3A	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-8682501EA CD54HC173F3A	Samples
CD54HCT173F3A	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-8875901EA CD54HCT173F3A	Samples
CD74HC173E	ACTIVE	PDIP	N	16	25	Green (RoHS & no Sb/Br)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC173E	Samples
CD74HC173M	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC173M	Samples
CD74HC173M96	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC173M	Samples
D74HC173M96G4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC173M	Samples
CD74HC173MG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC173M	Samples
CD74HC173PW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HJ173	Samples
CD74HC173PWR	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HJ173	Samples
CD74HCT173E	ACTIVE	PDIP	N	16	25	Green (RoHS & no Sb/Br)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT173E	Samples
CD74HCT173M	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT173M	Samples
CD74HCT173M96	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT173M	Samples
CD74HCT173MG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT173M	Samples

<sup>(1)</sup> The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.

## PACKAGE OPTION ADDENDUM



24-Aug-2018

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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#### OTHER QUALIFIED VERSIONS OF CD54HC173, CD54HC173, CD74HC173, CD74HC173:

Catalog: CD74HC173, CD74HCT173

Military: CD54HC173, CD54HCT173

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product





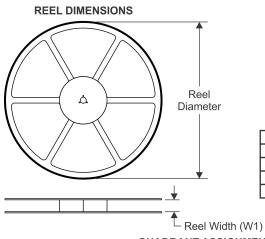
24-Aug-2018

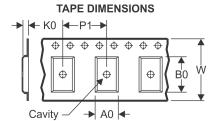
• Military - QML certified for Military and Defense Applications

## PACKAGE MATERIALS INFORMATION

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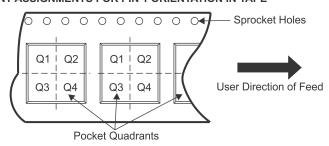
## TAPE AND REEL INFORMATION





_	_	
		3
	B0	Dimension designed to accommodate the component length
	K0	Dimension designed to accommodate the component thickness
	W	Overall width of the carrier tape
	P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74HC173M96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD74HC173PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
CD74HCT173M96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1

www.ti.com 18-Aug-2014



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74HC173M96	SOIC	D	16	2500	333.2	345.9	28.6
CD74HC173PWR	TSSOP	PW	16	2000	367.0	367.0	35.0
CD74HCT173M96	SOIC	D	16	2500	333.2	345.9	28.6

## D (R-PDS0-G16)

## PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



## D (R-PDSO-G16)

## PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.





SMALL OUTLINE PACKAGE



- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



#### 14 LEADS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

## N (R-PDIP-T\*\*)

## PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



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